



AT50-AX Templates





Nitride Solutions Inc.

Sapphire

Wafer Diameter	50.3mm
Orientation (c->m)	+0.2
Backside Roughness	Fine Ground

AlN

Orientation (major flat)	m-plane (AlN)
.....	
Thickness (measurement by white light)	
Avg	0.5 $\mu\text{m} \pm 0.05 \mu\text{m}$
(σ /Avg)	< 2%
.....	
Crystal Quality (FWHM)	
[002] XRD Linewidth	< 100 arcsec
[102] XRD Linewidth	< 340 arcsec
.....	
Transmission	>80% (@ 280 nm)
.....	
Exclusion Zone	3 mm
.....	
Surface Morphology	
AFM (R_z)	< 1 nm